

**Search Notes**

Application/Control No.

10/776,431

Examiner

Cong-Lac Huynh

Applicant(s)/Patent under  
Reexamination

ABBAR ET AL.

Art Unit

2178

**SEARCHED**

Class	Subclass	Date	Examiner
715	500	10/11/2006	CLH
	509	10/11/2006	CLH
	529	10/17/2006	CLH
707	6	10/11/2006	CLH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
715	500	10/11/2006	CLH
Interference Search History Printout		10/11/2006	CLH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (US PAT, USPGPUB, JPO, EPO, Derwent)	10/11/2006	CLH
ACM	10/17/2006	CLH
IEEE	10/25/2006	CLH
ProQuest	10/25/2006	CLH